

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/010,657	ALTHIN ET AL.	
Examiner		Art Unit		Page 1 of 1
Jack P Nguyen		2152		

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,461,371	10-1995	Matsumoto et al.	340/825.25
	B	US-6,337,856	01-2002	Schanhals et al.	370/352
	C	US-6,748,424	06-2004	Usuda, Hiroshi	709/217
	D	US-2002/0077905	06-2002	Arndt et al.	705/14
	E	US-5,351,186	09-1994	Bullock et al.	705/1
	F	US-2002/0068991	06-2002	Fitzsimmons, Robert L. JR.	700/214
	G	US-6,128,549	10-2000	Swartz et al.	700/225
	H	US-6,459,388	10-2002	Baron, John M.	340/996
	I	US-6,714,797	03-2004	Rautila, Heikki	455/552.1
	J	US-6,785,539	08-2004	Hale et al.	455/422.1
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

<sup>1</sup>A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.